

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)

[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
**IEEE Xplore**  
RELEASE 1.3

 Welcome  
 United States Patent and Trademark Office

**IEEE Xplore**  
 1 Million Documents  
 1 Million Users

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
[» Search Results](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **0** of **1069805** documents.  
 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

### Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.


☐ Check to search within this result set

### Results Key:

**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

### Results:

No documents matched your query.

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [O Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to](#)

Copyright © 2004 IEEE — All rights reserved

9-10-04

## Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

## Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

## Full-Text Only

- ☐ Access the IEEE Enterprise File Cabinet

 Print Format

Your search matched **14** of **1069805** documents.  
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set**Results Key:**

**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

**1 Cost reduction and evaluation of a temporary faults detecting technique**

Anghel, L.; Nicolaidis, M.;

Design, Automation and Test in Europe Conference and Exhibition 2000.

Proceedings , 27-30 March 2000

Pages:591 - 598

[\[Abstract\]](#)   [\[PDF Full-Text \(92 KB\)\]](#)   IEEE CNF

**2 Evaluation of a soft error tolerance technique based on time and/or space redundancy**

Anghel, L.; Alexandrescu, D.; Nicolaidis, M.;

Integrated Circuits and Systems Design, 2000. Proceedings. 13th Symposium on , 18-24 Sept. 2000

Pages:237 - 242

[\[Abstract\]](#)   [\[PDF Full-Text \(504 KB\)\]](#)   IEEE CNF

**3 Separate dual-transistor registers: a circuit solution for on-line testing of transient error in UDMC-IC**

Yi Shao; Dey, S.;

On-Line Testing Symposium, 2003. IOLTS 2003. 9th IEEE , 7-9 July 2003

Pages:7 - 11

[\[Abstract\]](#)   [\[PDF Full-Text \(336 KB\)\]](#)   IEEE CNF

**4 On-chip TEC-QED ECC for ultra-large, single-chip memory systems**

Alzahrani, F.; Chen, T.;

Computer Design: VLSI in Computers and Processors, 1994. ICCD '94.

Proceedings., IEEE International Conference on , 10-12 Oct. 1994

Pages:132 - 137

[\[Abstract\]](#)   [\[PDF Full-Text \(448 KB\)\]](#)   IEEE CNF

**5 Circuit simulations of alpha-particle-induced soft errors in MOS dynamic**

9-10-04



# IEEE Xplore®

RELEASE 1.8

Welcome  
United States Patent and Trademark Office

IEEE Xplore®  
1 Million Documents  
1 Million Users

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
[» Search Results](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **14** of **1069805** documents.  
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

### Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.


☐ Check to search within this result set

### Results Key:

**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

#### 1 Cost reduction and evaluation of a temporary faults detecting technique

Anghel, L.; Nicolaidis, M.;

Design, Automation and Test in Europe Conference and Exhibition 2000.

Proceedings, 27-30 March 2000

Pages:591 - 598

[\[Abstract\]](#)   [\[PDF Full-Text \(92 KB\)\]](#)   IEEE CNF

#### 2 Evaluation of a soft error tolerance technique based on time and/or space redundancy

Anghel, L.; Alexandrescu, D.; Nicolaidis, M.;

Integrated Circuits and Systems Design, 2000. Proceedings. 13th Symposium on, 18-24 Sept. 2000

Pages:237 - 242

[\[Abstract\]](#)   [\[PDF Full-Text \(504 KB\)\]](#)   IEEE CNF

#### 3 Separate dual-transistor registers: a circuit solution for on-line testing of transient error in UDMC-IC

Yi Shao; Dey, S.;

On-Line Testing Symposium, 2003. IOLTS 2003. 9th IEEE, 7-9 July 2003

Pages:7 - 11

[\[Abstract\]](#)   [\[PDF Full-Text \(336 KB\)\]](#)   IEEE CNF

#### 4 On-chip TEC-QED ECC for ultra-large, single-chip memory systems

Alzahrani, F.; Chen, T.;

Computer Design: VLSI in Computers and Processors, 1994. ICCD '94.

Proceedings., IEEE International Conference on, 10-12 Oct. 1994

Pages:132 - 137

[\[Abstract\]](#)   [\[PDF Full-Text \(448 KB\)\]](#)   IEEE CNF

#### 5 Circuit simulations of alpha-particle-induced soft errors in MOS dynamic

9-10-04